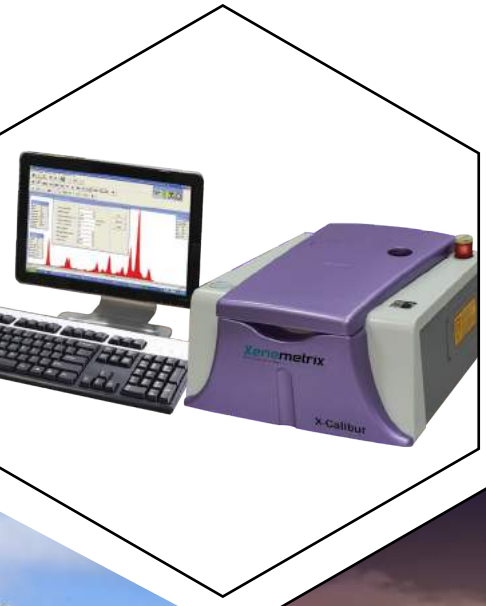
Xenemetrix
The Power to Change Energy Into Information

Systems Catalog

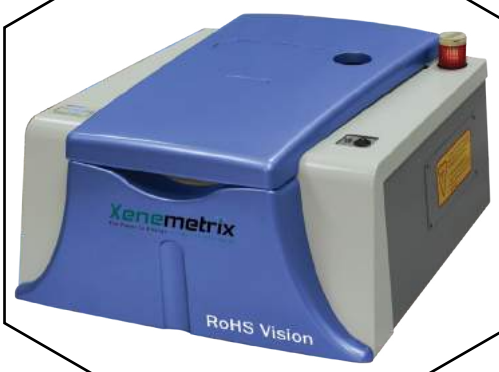
ED-XRF Spectrometers

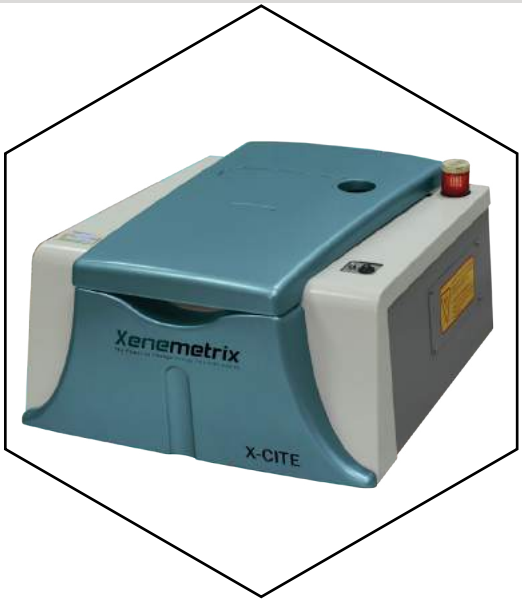
For over 30 years Xenemetrix Ltd. specializes in the design, development, production and marketing of Energy-Dispersive X-Ray Fluorescence (ED-XRF) systems


Xenemetrix
X-Calibur


Xenemetrix
Genius IF


Xenemetrix


Xenemetrix
RoHS Vision



ED-XRF Spectrometers

Energy-Dispersive X-Ray Fluorescence (ED-XRF) systems spectroscopy is one of the simplest, most accurate and economical analytical methods for determination of chemical composition for many types of materials. We combine the latest technological developments with innovative engineering, to provide cost-effective solutions to a wide range ofindustries and applications. An emphasis on quality combined with ongoing research and development has granted the company an international reputation for excellence.

innovative technologies

Xenemetrix continuously develops highly innovative XRF technology solutions suitable for today's ever-growing analytical challenges, performing non-destructive elemental analysis while providing detection limits from parts-per-million (ppm) down to sub ppm.

Spectroscopy advantages

The field of X-ray fluorescence (XRF) spectroscopy is challenging and exciting, with advantages such as easy sample preparation, non-destructive rapid multi-element analysis, and the ability to screen unknowns in a wide arrayof sample matrices such as liquids, solids, slurries, powders, pastes, thin films, air filters, and many others.
The technique requires minimum if any sample preparation, and suitable for almost all sample types and shapes.

Table of Contents

About Xenemetrix

ED-XRF Elemental Analysis

ED-XRF is relatively simple and inexpensive elemental analysis technology compared to other techniques. XRF found its place in many different types of analytical laboratories. Using ED-XRF allows measuring a wide range of elemental concentrations without the need for complicated sample preparations (heating or destroying the sample). Samples can be measured in the form of loose powders or pressed into pellets and ready for measurement within seconds. Because of these advantages the ED-XRF technique has a broad appeal to research, industrial, and quality assurance analysis, and offers a perfect complement to other types of analytical equipment in the analytical lab.

Variety of Applications

ED-XRF can be used for a tremendous variety of elemental analysis applications. It can be used to measure most element in the periodic table, ranging from ppm, sub ppm to nearly 100 percent concentrations. It can be used for monitoring major components in a product or process or the addition of minor additive. Xenemetrix is strongly committed to comply with customers' needs by offering a broad range of powerful, robust, cost-effective and easy-to-use instruments, perfectly suited for any lab settings. Customization is supported by Xenemetrix professional application engineering team, who are dedicated to configure and implement the perfect solution to your specific research needs.

Xenemetrix Products Line

Portable system

P-Metrix - Bringing out the Power of Laboratory Spectrometer to the field. The portable system can easily be transported to the job site, battery powered including touchscreen. When the task calls for fast, real time, high quality results in the field, the mobile spectrometer is the perfect answer for the job.

Bench Top systems

X-Cite, X-Calibur, Genius IF & RoHS - The bench top spectrometers offer a fast and non-destructive, cost-effective analytical solution in today's market for variety elemental analysis tasks. The compact spectrometers fit comfortably on a traditional laboratory bench.

Laboratory systems

Nova, Apollo & Vega - Laboratory spectrometers offer the ultimate non-destructive solution in elemental analysis applications. The versatile laboratory spectrometers can analyze high-end applications down to sub ppm, light elements and sensitive analysis of Particulate Matter Collected on Air Filter Samples while the analytical chamber can accommodate samples of different shapes and sizes.

Application
Petrochemical & Petroleum

ED-XRF offers a low cost quantitative analysis method that achieves fast results that complies with ASTM standards and regulations.
Xenemetrix systems provide accurate determination of trace amount to percent levels of elements in fuels, oils, and lubricants. Our superior solutions cover the full refinery production process, starting from research and development up to process and quality control.
Used in a wide variety of petrochemical & petroleum applications to identify elements and determine the actual elemental concentrations present in a variety of matrices (solid, powdered, and liquid samples).

- **Compliance with the ASTM method at low concentration sulfur** - Sulfur is a major element of importance because when burns it forms sulfuric acid in the atmosphere and has harmful impact on the human health and on the environment.
- **Manganese in Gasoline** - Manganese is another anti-knock additive that is used primarily in Canada at very low ppm concentrations. This application can be obtained with ED-XRF instruments.
- **Chlorine in Crude Oil** - Crude oil is desalinated to remove salts that are present by nature. Chlorine in crude oil needs to be according to ASTM before the oil can be refined.
- **Nickel and Vanadium in Crude Oil** - These elements can poison catalysts used in the refining process.
- **Sulfur, Nickel, and Vanadium in Residual Oil** - These elements are monitored for either emissions or recovery purposes.
- **Sulfur & Carbon in Coke** - Low content of Sulfur and Carbon in Coke materials are valuable for production.
- **Mg, P, S, Ca, Ba, Zn, Mo in Lubricating Oils** - Lube oils contains several additives, some of them are stabilizers, and others improve lubrication. Several ASTM methods cater for these additives using ED-XRF quantitative analysis.
- **S, Cl, As, Pb, Cd in Waste Oil and Waste Fuel Oil** - Waste oils are used lubrication oil which are used in several oil-fired power plants and kilns. These are monitored for toxic metals chlorine and sulfur for environmental protection.

Key applications include:
- ASTM D7212, D7220, D7039, D7751, D5453 and ISO 8754, 13032, 20846, 20884, 13032, 20847, IP531
- ASTM D4294 (sulfur analysis)
- Monitoring of Mo, Ba, Mn
- ASTM D6481 (unused lubricating oils): Ca, P, Zn, S
- Monitoring of wear metals: Sb, Sn, Mo, Ti, Ni, Cd, Fe, V, Pb, Cr, Cu
- Analysis of P, S, Ca & Zn in Lube Oil

Mining & Geochemistry

ED-XRF spectrometers provide on-site quantitative analysis of mining materials and minerals. Xenemetrix advanced ED-XRF spectrometers reduce the time of receiving results from days to seconds, making it also ideal for the exploration industry, delivering excellent precision and accuracy of critical measurements, as well as the low limits of detection (LOD).

- **Cement** - ED-XRF is being used to analyze raw meal, clinker, and the final cement product (Na, Mg, Al, Si, S, K, Ca, and Fe in Cement, Clinker, and Raw Meal).
- **Limestone** is the major component of cement. It is one of the most common minerals and ED-XRF is a popular method being used for its analysis.
- **Sand** is a component of cement, but is mainly used for producing glass. Particularly valuable for glassmaking is low iron, which forms an important sub-application.
- **Clays** are used in a variety of ceramic goods, artifacts, bricks and other finished products. Monitoring Ti and Fe content is important for color control.
- **Bauxite** is a mineral that is high in aluminum and forms the most important source of aluminum for metal production (Al, Si, Ti, and Fe in Bauxite).
- **Phosphate rock** is the major source of phosphorus used in fertilizer and phosphoric acid production. ED-XRF is commonly used to measure the rock, phosphoric acid solutions, and fertilizer (P, S, Ca, Fe in Phosphate Rock and Fertilizer).

Specialized applications:

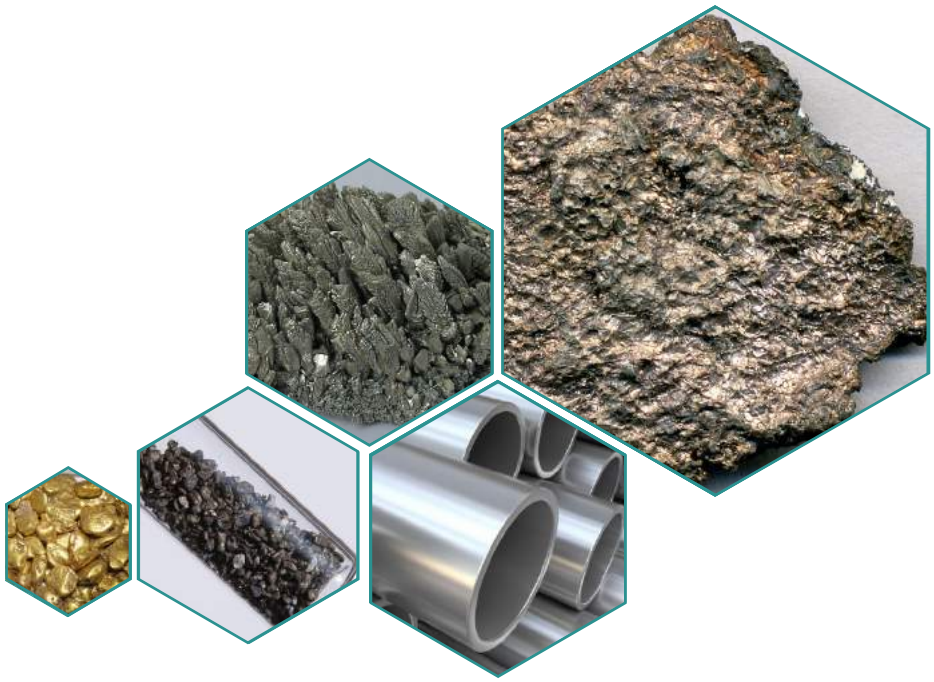
- Iron, uranium
- Coal, diamonds, limestone
- Oil shale, rock salt and potash
- Precious metals – gold (Au), silver (Ag), platinum (Pt), palladium (Pd)
- Rare earth elements
- Cassiterite, cadmium and antimony, Cd, Sb
- Light elements, such as C, N, f, Na, Mg, Al, Si, P, S and Cl

Metals & Alloys

ED-XRF plays a dominant role in quality control of the various metal industry processes. Non-destructive elemental analysis can be performed in each step of the process, from ores to finished alloys.
ED-XRF is capable of easy and fast sorting between different steel grades, as well as forming a convenient for QA processing analytical tool that provides immediate results.

Specific applications include:

- **Alloy Analysis**- Alloy analysis using Xenemetrix spectrometers has become a standard practice. Xenemetrix spectrometers identify most alloys and perform complete chemical analysis within a few seconds. High-level spectrometers perform quick and easy sorting and identification of all classes of alloys including: Iron, steel - low alloy, stainless steel, copper, brass, bronze, aluminum bronze, leaded brass and bronze, aluminum, nickel alloys, zinc alloys, cobalt alloys, titanium alloys , solders-tin, lead and silver.
- **Precious Metals** - Precious metals are always of interest for jewelry, industrial use, and investment purposes. With Xenemetrix bench-top spectrometers, metals can be detected and tested for content and purity with very low operational costs and no need for sample preparations. The essential advantage of using Xenemetrix analyzers is high precision and accuracy. The analyzers makes it possible to determine the elemental content of items offered for sale and their karat value within seconds.
- **Ores, Slags, Feeds, Concentrates, and Tailings** - ED-XRF plays an important role in each step of the metal production process. Large and small components are analyzed with ED-XRF instruments.
- **Silicon Metal** - silicon is a very important metalloid in the semiconductor industry and high purity is required. ED-XRF is often used to monitor high silicon sands for impurities, and can be used throughout the refining process and during the wafer production. Specialized high performance ED-XRF equipment is specifically designed for wafer analysis.
- **Metal Foil Thickness** - Foils are produced from every conceivable elemental metal. The thickness of thin foils can be easily measured on-line by ED-XRF.



Cosmetics

Many additives in cosmetic products are mineral or organic with add-ons of elements that are measurable by ED-XRF.
Xenemetrix systems are ideal during the manufacturing process of cosmetic products, which need to be chemically analysed to ensure conforming to product specification and safety regulations, as well as achieving cost-effectiveness in the manufacturing process.

Several well-known applications include:

- **Titanium and Zinc in Sunscreen**- Titanium dioxide is used in most sunscreens to help prevent UV radiation burns. The concentration is high and can easily be measured by ED-XRF.
- **Iron, Titanium, and Zinc in Base Makeup**- Colored base makeup usually contain black iron oxide, red iron oxide, and titanium dioxide and/or zinc oxide which are white. The ratio of these oxides determines the shade.
  ED-XRF is used to measure total iron and other major components existing in makeup products.
- **Toxic Metals in Cosmetics**- Cosmetic component are usually analyzed for toxic components to ensure their safety. ED-XRF analyzers can be used for measuring toxic metals such as lead, cadmium, mercury, and arsenic in cosmetic products.
- **Metal Dyes in Cosmetics**- Some of the brightly colored dyes such as those composing eye shadows and fingernail polishes contain metallic dyes that can be measured by ED-XRF.

R&D and Academy

Modern research deals with the development of new forms of diagnostic technologies for different purposes, such as solutions for laboratory needs, devices and methods that deliver accurate and reliable results at a very high level of productivity.
Research and development units, material science, chemical engineering and electronics departments use the affordable ED-XRF spectrometers. ED-XRF makes great analysis and provides a study tool featuring all the capabilities of high-end systems with a full analytical software package. ED-XRF can measure larger sample volumes resulting in a better characterization of end products, and provides high accuracy and precision with excellent detection limits.
Xenemetrix is strongly committed to comply with research departments and academic professionals' needs by offering a broad range of powerful, robust, cost-effective and easy-to-use instruments, perfectly suited for any lab settings, supported by Xenemetrix professional application engineering team, dedicated to configure and implement the perfect solution to customers' specific research needs.

P-Metrix

Portable Field Laboratory

The P-Metrix is engineered to provide a portable field laboratory with safe and superior Energy Dispersive X-Ray Fluorescence (EDXRF) quantitative and qualitative analysis. P-Metrix is a highpower analyzer that incorporates performances and safety of a top-grade ED-XRF benchtop analyzer, combined with easy mobility, light weight, compact size and cost-effective benefits of a portable device and field engineered.

- **Non-destructive** Elemental analysis **Na (11) to U (92)** from ppm to 100% concentrations
- **Silicon Drift Detector (SDD)** higher-count rate and resolution, down to 125eV for improved analysis
- **Self service and maintenance** easy replacement of instruments components
- **X-Ray Source** of 50kV, 10W with Rh anode providing onsite lab quality for complex field applications and high performance
- **Automatic calibration**, **adjustable tube and filters**
- **Large testing chamber** & Sample camera

Technical specifications

Detector	Silicon Drift Detector (SDD) with Be window resolution down to 125eV
Excitation	X-Ray Source of 50kV, 10W with Rh anode (Ag\W\Au optional)
Excitation Type	Direct with filters
Elemental Analysis	Na (11) - U (92)
Detectable Concentration	ppm - 100%
Weight	16 Kg
Dimensions	L40.2x W30.2 x H24 Chamber: 30.2 x 26.45 x 10 cm
Customized Tube Filters	7 software selectable
Customized Collimator	0.3 mm - 3 mm
Camera	CMOS video camera HD
Work Environment	Air / Helium / Vacuum
Power Supply	110-230VAC 50/60Hz
Portable Power Supply	4 hour Li-ion battery
Hardware	Integrated PC with touchscreen, SSD hard drive, GPS, GPRS, WiFi, Mini HDMI, USB interfaces
Software	Analytix analysis package (Running under Microsoft Windows™ OS)
Optional Software	Advanced Fundamental Parameters analysis, Standartless Software, libraries
Options	Sealed rugged carrying case, Sample cup holder with sample in-tray sensor, 12 V DC car charging cable

X-Cite

Low Cost Compact Benchtop

The compact cost-effective spectrometer fits comfortably on a traditional laboratory bench and include a fully integrated computer system, six customizable filters and a sample tray.
The Xenemetrix bench-top spectrometer use a high resolution detector and a powerful X-Ray tube and a sample camera in order to accommodate samples of various sizes and types.

- **Non-destructive elemental** analysis
  Na (11) - U (92) from ppm to 100% concentrations
- **Six customizable filters** for fast and accurate determination of trace and minor elements
- **Compact geometry**
- **Sample camera**
- **Sample tray** with 8/16 positions
- **Silicon Drift Detector** (SDD) enables extremely high count rate applications with excellent energy resolution

Technical specifications

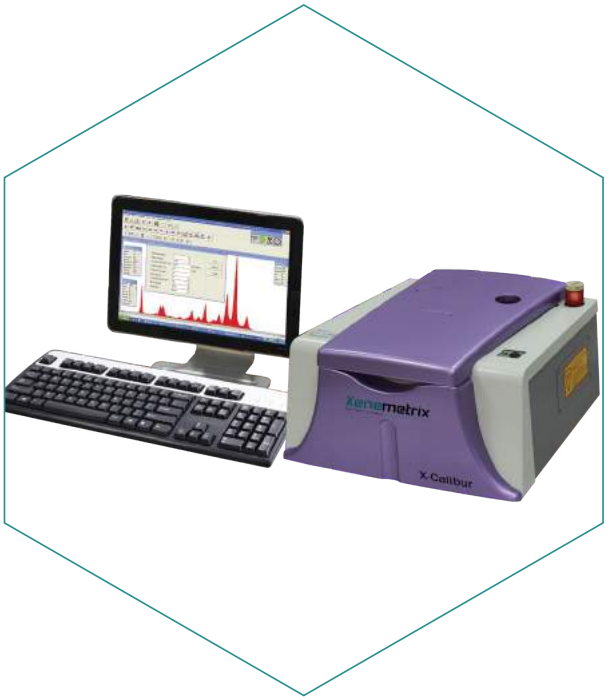
Detector	Silicon Drift Detector (SDD) with Be window resolution down to 125eV
Elemental Analysis	Na (11) - U (92)
Detectable Concentration	ppm - 100%
Excitation	X-ray Source of 40kV, 18W with Rh/Ag/Mo/W/Pd anode
Excitation Type	Direct with filters
Autosampler	8/16 positions
Weight	50kg
Dimensions	System: L55 x W55 x H32 Chamber: 22 x 22cm, H=5cm
Customized Tube Filters	6 software selectable
Customized Collimator	0.3 mm - 3 mm
Work Environment	Air / Helium / Vacuum
Power Supply	110-230VAC 50/60Hz
Software	Analytix analysis package (Running under Microsoft Windows™ OS)
Optional Software	Advanced Fundamental Parameters analysis, Standartless Software, libraries
Options	Sample spinner, CCD camera

X-Calibur

Compact High Performance Benchtop

The compact benchtop spectrometer with unique front - Anode geometry and high power excitation X-ray source fits comfortably on a traditional laboratory bench and include a fully integrated computer system, six customizable filters, sample tray and a sample camera.
The Xenemetrix bench-top spectrometer use a high resolution detector and a powerful X-Ray tube, in order to accommodate samples of various sizes and types. The X-Calibur has an optional Ultra-thin detector window that provides superior performance for low Z elements (Light Element) analysis.

- **Non-destructive elemental** analysis
  Na (11) - U (92) from ppm to 100% concentrations
- **Six customizable filters** for fast and accurate determination of trace and minor elements
- **Sample tray** with 8/16 positions
- **Silicon Drift Detector** (SDD) enables extremely high count rate applications with excellent energy resolution, suitable for both high and low Z elements (Optional LE detector)
- **Unique front - Anode geometry** combined with an advanced optical design, permits extremely close coupling with the sample resulting in increased sensitivity
- **Compact geometry & sample camera**



Technical specifications

Detector	Silicon Drift Detector (SDD) with Be window resolution down to 125eV
Elemental Analysis	Na (11) - U (92)
Detectable Concentration	ppm - 100%
Excitation	X-Ray Source of 50kV, 50W with Rh/Ag/Mo/W/Pd anode
Excitation Type	Direct with filters
Autosampler	8/16 positions
Weight	50kg
Dimensions	System: L55 x W55 x H32 Chamber: 22 x 22cm, H=5cm
Customized Tube Filters	6 software selectable
Customized Collimator	0.3 mm - 3 mm
Work Environment	Air / Helium / Vacuum
Power Supply	110-230VAC 50/60Hz
Software	Analytix analysis package (Running under Microsoft Windows™ OS)
Optional Software	Advanced Fundamental Parameters analysis, Standartless Software, libraries
Options	Light elements SDD, Sample spinner, CCD camera

Genius IF

Unique Secondary Target Benchtop

The compact spectrometer provides a non-destructive qualitative and quantitative determination from Na (11) - U (92) , providing detection limits from sub-ppm to high weight percent concentrations. The Genius IF has a unique patented geometry combining eight secondary targets, with eight customizable tube filters used in direct excitation mode, to allow optimal excitation of all elements that can be detected in ED-XRF. The WAG (Wide Angle Geometry) patented secondary target technique provides the best results for major, minor and trace element analysis.

- **Non-destructive elemental analysis**
  Na (11) - U (92) starting from Sub ppm to 100% concentrations
- **Eight secondary targets** - A unique patented geometry that combines eight secondary targets and eight customizable tube filters for fast and accurate determination of trace and minor elements
- Optional **SDD light elements** optimized detector for light elements analysis
- **Sample tray with 8/16 positions**
- **Silicon Drift Detector (SDD)** enables extremely high count rate applications with excellent energy resolution, down to 125eV

Technical specifications

Detector	Silicon Drift Detector (SDD) with Be window resolution down to 125eV
Elemental Analysis	Na (11) - U (92)
Detectable Concentration	Sub ppm - 100%
Excitation	X-Ray Source of 50kV, 50W with Rh\Mo\Ag\W\Pd anode
Excitation Type	Direct with filters and secondary targets
Autosampler	8/16 positions
Weight	50kg
Dimensions	System: L55 x W55 x H32 Chamber: 22 x 22cm, H=5cm
Customized Tube Filters	8 software selectable
Customized Secondary Targets	8 software selectable
Customized Collimator	0.3 mm - 3 mm
Work Environment	Air / Helium / Vacuum
Power Supply	110-230VAC 50/60Hz
Software	Analytix analysis package (Running under Microsoft Windows™ OS)
Optional Software	Advanced Fundamental Parameters analysis, Standartless Software, libraries
Options	Light elements SDD, Sample spinner

RoHS

RoHS Analyzer

The Restriction of Hazardous Substances (RoHS) is a set of standards that limit the use of certain toxic metals in electrical and electronic equipment.
The Xenemetrix new RoHS uses a high resolution SDD detector, an integrated camera, and a powerful X-Ray tube with variable spot sizes to accommodate samples of various sizes and to measure the existence of extremely low levels of restricted substances.

- Accurately analyze restricted elements **Pb, Hg, Cd, Cr, Br**
- **Integrated camera and micro X-Ray spot** for full identification of the area of interest
- **Pre-calibrated automatic matrix** identification allows operation of non-technical personnel with high degree of confidence
- Intuitive and **user-friendly proprietary software**

Technical specifications

Detector	Fast SDD version 125 eV
Elemental Analysis	Pb, Hg, Cd, Cr, Br
Detectable Concentration	ppm - 100%
Excitation	X-Ray Source of 50kV, 50W with Mo anode
Excitation Type	Direct with filters
Weight	50kg
Dimensions	System: L55 x W55 x H32 Chamber: 22 x 22cm, H=5cm
Customized Tube Filters	6 software selectable
Customized Collimator	0.3 mm - 3 mm
Camera	CDD Camera
Work Environment	Air
Power Supply	110-230VAC 50/60Hz
Software	User-friendly Operator mode (Running under Microsoft Windows™ OS)

Nova

High Performances Laboratory System

Fast, accurate, easy-to-use spectrometer, equipped with robust hardware and powerful analytical software to achieve low detection limits. Using a multi-channel acquisition resolution provides superior peak-to-background ratio for improved detector response. Eight secondary targets models and eight filters, provide maximum sensitivity for fast and precise quantification in complex matrices. Targets can be fully customizable to achieve sub ppm detection limits in a wide range of elements. The integral design of the 10/20 positions autosampler permits minimal human intervention while allowing automatic and unattended operation.

- **Non-destructive elemental analysis**
  Na (11) - U (92) starting from Sub ppm to 100% concentrations
- **Silicon Drift Detector (SDD)** facilitates extremely high count rate
- **Improved peak to background ratio**, when using secondary target excitation
- **Eight filters and eight secondary targets**
- **Suitable for a larger range of applications** that had previously not been accessible

Technical specifications

Detector	Silicon Drift Detector (SDD) with Be window Resolution down to 125eV
Excitation	X-Ray Source of 300W, 60kV, Rh Anode (Mo, W, Pd optional)
Elemental Analysis	Na (11) - U (92)
Detectable Concentration	Sub ppm - 100%
Excitation Type	Direct with filters and secondary targets
Autosampler	10/20 positions chamber
Weight	110kg
Dimensions	Chamber: 28cm diameter, H=6cm
Customized Tube Filters	8 software selectable
Customized Secondary Targets	8 software selectable
Customized Collimator	0.3 mm - 3 mm
Work Environment	Air / Helium / Vacuum
Power Supply	110-230VAC 50/60Hz
Hardware	Integrated PC
Software	Analytix analysis package (Running under Microsoft Windows™ OS)
Optional Software	Advanced Fundamental Parameters analysis, Standartless Software, libraries
Options	Sample spinner

Vega

Light Elements High Power Spectrometer

The Xenemetrix Vega laboratory (ED-XRF) spectrometer offers ultimate non-destructive solution in light elements and rare earth elements analysis applications. High power excitation (400W), eight filters and eight secondary targets provide maximum sensitivity for fast and precise quantification, achieving sub ppm detection limits in a wide variety of elements.
Using the advance SDD LE with ultra thin window delivers lower electronic noise and higher count rates which translates to higher energy resolution and faster results, achieving low detection limits and superior peak-to-background ratio for improved detector response.

- **High power Non-destructive elemental analysis** of light elements starting from sub ppm to 100% concentrations
- **Silicon Drift Detector (SDD LE)** facilitates extremely high count rate applications with excellent energy resolution, suitable for both high and low Z elements
- **SDD LE with ultra thin window** for advanced light elements analysis
- Advanced **standardless fundamental parameters** software
- **Eight filters and eight secondary targets**

Technical specifications

Detector	Silicon Drift Detector (SDD LE) with ultra thin window light elements optimized resolution down to 125eV
Excitation	X-Ray Source of 400W, 60kV, Rh Anode (Mo\W\Pd\Ag optional)
Elemental Analysis	Na (11) - U (92), Light elements
Detectable Concentration	Sub ppm - %100
Excitation Type	Direct with filters and secondary targets
Autosampler	10/20 positions chamber
Weight	110kg
Dimensions	Chamber: 28cm diameter, H=6cm
Customized Tube Filters	8 software selectable
Customized Secondary Targets	8 software selectable
Customized Collimator	0.3 mm - 3 mm
Work Environment	Air / Helium / Vacuum
Power Supply	110-230VAC 50/60Hz
Hardware	Integrated PC
Software	Analytix analysis package (Running under Microsoft Windows™ OS)
Optional Software	Advanced Fundamental Parameters analysis, Standartless Software, libraries
Options	Sample spinner

Apollo

Sensitive Analysis for Air Quality Regulation

The analyzer can test inorganic air pollutant species while supporting compliance with US-EPA's air quality regulation requirements. Having the power to quantify the deposits of airborne particulates up to 60 elements. The Apollo is fast, accurate, easy to use, and achieves low detection limits. Capable of analysing filters without destruction and with no preparation or extraneous handling, the instrument ensure that the air filter sample can be preserved for future reference. Using secondary targets with varied voltages and emission currents, provides monochromatic excitation energy and an increased signal-to-noise ratio providing superior sensitivity.

- Sensitive analysis of **particulate matter collected on air filter**
- **Test for inorganic air pollutant species** while supporting compliance with the US-EPA's air quality regulation requirements
- **Non-destructive elemental analysis** of fine particles collected on Air Filters for elements Na (11) - U (92)
- **Eight filters and eight secondary targets**

Technical specifications

Detector	Silicon Drift Detector (SDD) with Be window resolution down to 125eV
Excitation	X-Ray Source of 400W, 60kV, Rh Anode
Elemental Analysis	Na (11) - U (92)
Detectable Concentration	Sub ppm - %100
Excitation Type	Direct with filters and secondary targets
Autosampler	10/20 positions chamber
Weight	110kg
Dimensions	Chamber: 28cm diameter, H=6cm
Customized Tube Filters	8 software selectable
Customized Secondary Targets	8 software selectable
Customized Collimator	0.3 mm - 3 mm
Work Environment	Air/Helium Purge and Vacuum Capable including valves fittings, hoses and He flow meter
Power Supply	115 VAC/60 Hz or 230 VAC/50 Hz
Hardware	Integrated PC
Software	Analytix analysis package (Running under Microsoft Windows™ OS)
Optional Software	Advanced Fundamental Parameters analysis, Standartless Software, libraries
Options	Sample spinner

Analytix

Easy creation of analytic procedures

Fundamental Parameters analysis:
The fundamental Parameter method Enables standardless calibrations, correlates between the measured X-ray intensities and the elemental concentrations in samples, based on X-ray physics and measured values of fundamental atomic parameters in the ED-XRF region of the spectra.

Advanced quantitative & qualitative analysis:
Predefined customized procedures for quantitative and qualitative spectroscopic analysis.

Fast analysis:
Quick and accurate spectral acquisition and qualitative analysis with auto-peak identification.

Deep analysis:
Advanced spectral acquisition and qualitative analysis, with six different sequential acquisitions and pre-defined procedures included.

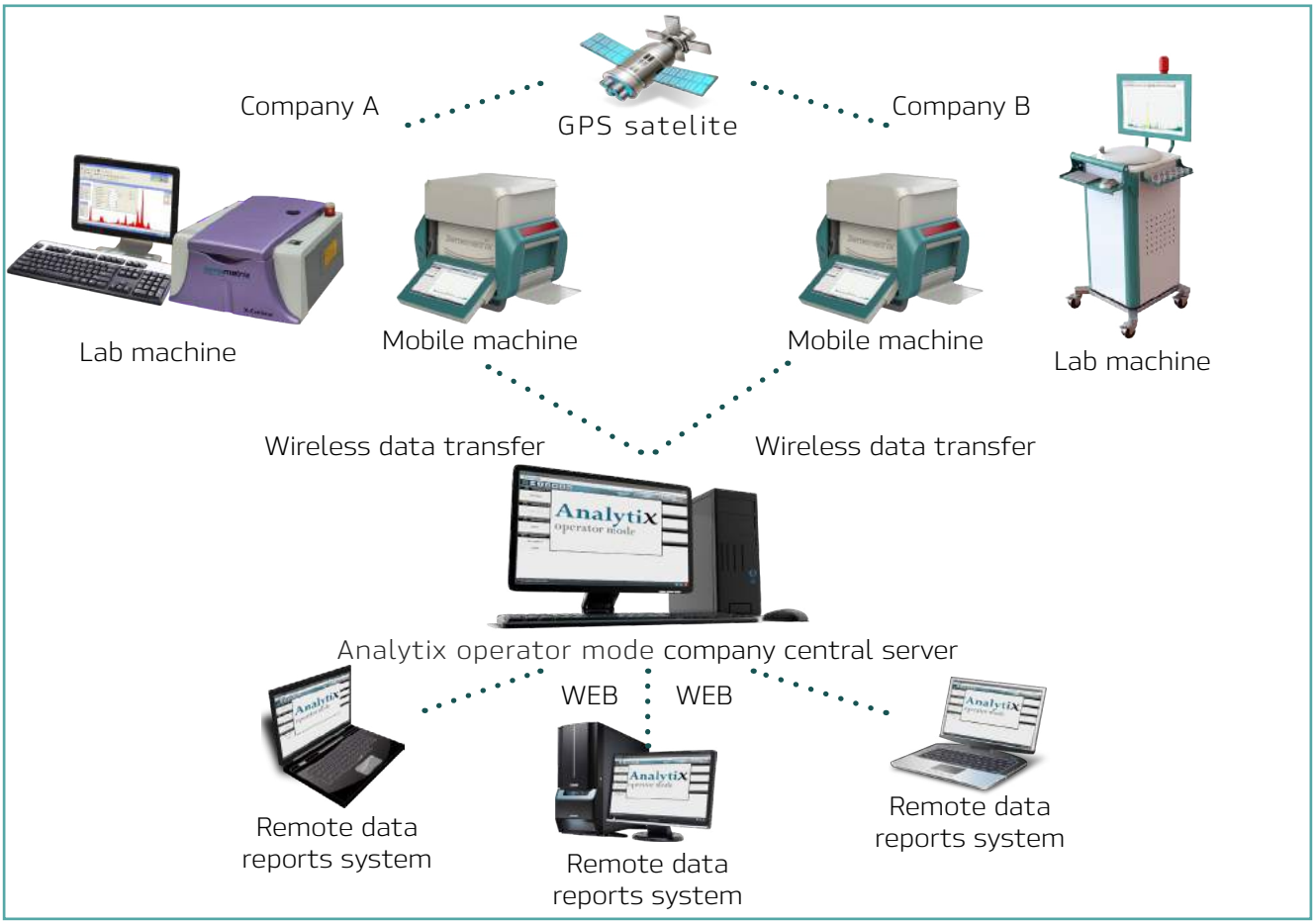
Auto-calibration:
Automatic energy shift correction calibration upon true samples.

Libraries:
Defining alloy grade, resulting composition of elements, providing quantitative analysis, composition and other properties of the alloy material.

Automatic energy calibration:
Normalization, matching and validation of tube intensity.

Analysis results features:
Manual Peak ID, User Annotation, Overlap and ROI.

Client-server network operator mode:
The Analytix operator mode enables storing data in the "cloud" - Suitable for organizations that utilize multiple systems and require a central control for both application and system maintenance.



Client-server operator mode

Analytix operator mode suits either compact portable analyzers that can easily be transported between sites or to a robust lab system that can be installed in a distributed laboratory.

Stand-alone / Client-server

Analytix operator mode can operate in a standalone mode wherein all data and results are stored locally, as well as in a client-server configuration wherein all results and data are updated in real-time or upon request to the company HQ server. This enables easy management of multiple systems at disperses global locations and collecting data from different sites into the company central server.

GPRS / Wi-Fi / LAN / GPS

Analytix software supports GPRS/Wi-Fi/ LAN/GPS connectivity, that enable location based data to be transferred immediately to the company's HQ server for reporting and monitoring.

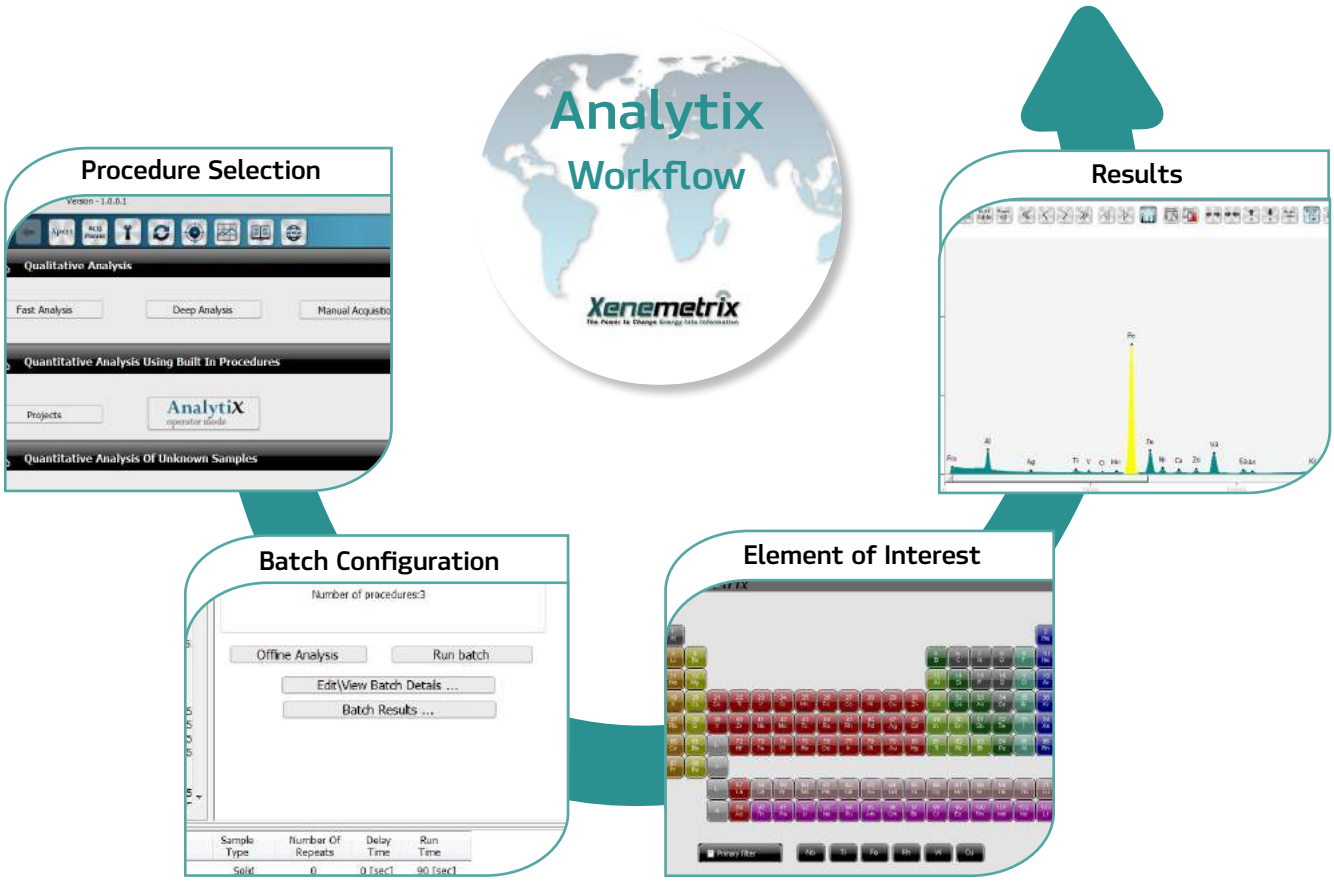
Fast processing

Analytix operator mode is an advanced software package with strong analytical capabilities. The user-friendly system enables an operator to perform multiple tests within a short time and at minimum effort.

Analytix Workflow

High-end ED-XRF solution with real-time analytic data collection - matching your analytical needs

Easy creation of analytic procedures



Xenemetrix Headquarters
Ramat Gabriel Industrial Zone, 6 Hatikshoret St.
Migdal Haemek 2310901, Israel
Tel: +972-4-9891313 Fax: +972-4-9891323
E-mail: info@xenemetrix.com
Website: www.xenemetrix.com

Xenemetrix is a leading designer, manufacturer and marketer of Energy-Dispersive X-Ray Fluorescence (ED-XRF) systems. With more than 30 years experience, Xenemetrix continues to develop highly innovative technologies and solutions suitable for today's ever-growing analytical challenges.

Xenemetrix combines the latest technological developments with innovative engineering, to provide cost-effective solutions to a wide range of industries and applications.

Worldwide Distributions:
North America, Latin America, Europe, Asia & Pacific, Australia, Africa & Middle East